



Cite this: *Phys. Chem. Chem. Phys.*,
2018, 20, 2914

Correction: Direct characterization of graphene doping state by *in situ* photoemission spectroscopy with Ar gas cluster ion beam sputtering

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DOI: 10.1039/c7cp90282d

rsc.li/pccp

Correction for 'Direct characterization of graphene doping state by *in situ* photoemission spectroscopy with Ar gas cluster ion beam sputtering' by Dong-Jin Yun *et al.*, *Phys. Chem. Chem. Phys.*, 2018, **20**, 615–622.

The authors would like to correct the grant number given in the Acknowledgements of the published article. The correct Acknowledgements should read as follows:

This work was supported by a grant from the Fundamental R&D program for Core Technology of Materials funded by the National Research Foundation (NRF) of Korea (NRF-2017R1D1A1B03034322). This work was supported by the Samsung Advanced Institute of Technology.

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.

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